

# ELECTRONIC INFORMATION DISCLOSURE STATEMENT

Electronic Version v18

Stylesheet Version v18.0

Title of Invention	[METHODS AND SYSTEMS FOR RESISTIVITY ANISOTROPY FORMATION ANALYSIS]
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Application Number : 10/604492

Confirmation Number:

First Named Applicant: Cheng Liu

Attorney Docket Number: 20.2807

Art Unit: 2863

Examiner: V. TAYLOR

Search string: ( 5656930 or 6218841 or 5886526 or 6092024 or 5966013 or 5461562 or 5550473 or 3166709 or 20020149997 or 20030018434 ).pn

## US Patent Documents

Note: Applicant is not required to submit a paper copy of cited US Patent Documents

init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
W	1	5656930	1997-08-12	Hagiwara		324	339
W	2	6218841	2001-04-17	Wu		324	338
W	3	5886526	1999-03-23	Wu		324	338
W	4	6092024	2000-07-18	Wu		702	007
W	5	5966013	1999-10-12	Hagiwara		324	339
W	6	5461562	1995-10-24	Tabanou et al.		702	011
W	7	5550473	1996-08-27	Klein		324	339
W	8	3166709	1959-04-17	Doll		324	339

## US Published Applications

Note: Applicant is not required to submit a paper copy of cited US Published Applications

init	Cite.No.	Pub. No.	Date	Applicant	Kind	Class	Subclass
W	1	20020149997	2002-10-17	Zhang et al.	A1	367	018
W	2	20030018434	2003-01-23	Kriegshauser et al.	A1	707	007

## Signature

Examiner Name

3/31/2005

FORM PTO-1449			ATTY. DOCKET NO. 20.2807	SERIAL NO. 10/604,492	
<p>LIST OF INFORMATION PROVIDED BY APPLICANT</p> <p>Use several sheets if necessary)</p> <p>OCT 24 2003 U.S. PATENT &amp; TRADEMARK OFFICE OCT 24 2003 U.S. PATENT &amp; TRADEMARK OFFICE</p>			<p>APPLICANT: Cheng Bing Liu et al.</p> <p>FILING DATE: 07/25/2003</p> <p>GROUP N/A</p>		
REFERENCE DESIGNATION U.S. PATENT DOCUMENTS					
Examiner Initial		Document No.	Date	Patentee	
	AA				
	AB				
	AC				
	AD				
	AE				
	AF				
	AG				
	AH				
	AI				
	AJ				
	AK				
	AL				
FOREIGN PATENT DOCUMENTS					
		Document No.	Date	Country	Translation Yes No
	AM				
	AN				
OTHER INFORMATION PROVIDED (AUTHOR, TITLE, DATE, PLACE OF PUBLICATION, PERTINENT PAGES, ETC.)					
WR	AO	Shray, Frank et al., Evaluation of Laminated Formations Using Nuclear Magnetic Resonance and Resistivity Anisotropy Measurements, SPE 72370, October 17-19, 2001, pp. 1-17.			
	AP	LAST ITEM			
EXAMINER			DATE CONSIDERED 3/31/2005		

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

1. The attached cited information should not be construed as an admission that any of the above items are prior art to the subject invention.
2. This is not a representation that a search has been made.